Refine Search

Search Results -

Terms	Documents
(external pin$1) near4 (transfer$5 near3 address$5)	1

Database:
US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
US OCR Full-Text Database
EPO Abstracts Database
JPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins

Search: L22

Refine Search | Recall Text | Clear | Interrupt

Search History

DATE: Wednesday, May 10, 2006 Printable Copy Create Case

Set Name side by side	Query	Hit Count	Set Name result set
DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ			
L22	(external pin$1) near4 (transfer$5 near3 address$5)	1	L22
L21	(external pin) near4 (transfer$5 near3 address$5)	1	L21
L20	714/$.ccls.	53765	L20
L19	l13 same L17	31	L19
L18	l13 and L17	208	L18
L17	(generat$5 near3 address$5) same L14	6735	L17
L16	l13 and L15	866	L16
L15	(generat$5 near3 address$5) and L14	25780	L15
L14	(read$5 same memory) same (stor$5 near3 data)	210075	L14
L13	detect$5 near3 ((memory or memories) near3 (error$1 or defect$1 or fault$1))	7336	L13
L12	L11 and (sequence controll$5)	9	L12
L11	(built-in self test$5) and l1	327	L11

L10	(built-in self test$5) and l2	26	L10
L9	(sequence controll$5) and l2	7	L9
L8	(scan chain$5) and l2	9	L8
L7	(scan chain$5) and l3	2	L7
L6	(integrated circuit$1) and l3	28	L6
L5	l3 and L4	2	L5
L4	(external near4 analysis) and l1	298	L4
L3	(data register$1) and l2	81	L3
L2	(address near3 generat$5) same l1	300	L2
L1	diagnos$5 same (memory or memories)	28824	L1

END OF SEARCH HISTORY